

Coming soon

Time-of-Flight SIMS

Sleek New Design
PHI nanoTOF 3



The 7th Generation of TOF-SIMS from PHI

- NEW appearance with sleek design, reduced footprint, and reduced power consumption
- NEW fully automated stage design for reliable, high-throughput sample handling with in-vacuum parking
- NEW bismuth LMIG cluster ion emitter with improved spatial resolution

Patented Parallel Imaging MS/MS Spectrometer

- From flat to rough sample surfaces, the entire range is covered by the 7th generation of PHI's triple-focus mass analyzer
- Parallel Imaging MS/MS takes TOF-SIMS peak identification from "I think" to "I know!"
- Lossless and high sensitivity tandem MS analysis of peaks down to < 20 ppm abundance

Patented Turn-key Dual-Beam Charge Neutralization

- NEW combination of pulsed low-energy electrons and low-energy Ar⁺ ions for robust and truly turn-key analysis in both +ve and -ve ion polarities

Reliable automation and remote operation

- Highly configurable queuing system for automated unattended analysis and maximum efficiency
- Fully remote operation and advanced remote diagnostics

